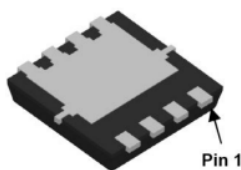
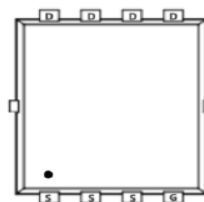
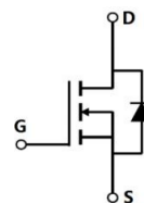


Main Product Characteristics:

V_{DSS}	60V
$R_{DS(on)}$	12m Ω (typ.)
I_D	33A


DFN 3*3-8L

Pin Assignments

Schematic Diagram
Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- AEC-Q101 qualified


Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
$I_D @ T_A = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ①	33	A
I_{DM}	Pulsed Drain Current ②	108	
P_D	Power Dissipation ③	39	W
EAS	Single Pulse Avalanche Energy@L=0.3mH	75	mJ
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-to-Source Voltage	± 20	V
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	3.2	$^{\circ}\text{C}/\text{W}$

Electrical Characterizes @ $T_A=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	60	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	12	17	m Ω	$V_{GS}=10\text{V}, I_D=30\text{A}$
		—	14	25		$V_{GS}=4.5\text{V}, I_D=20\text{A}$
$V_{GS(th)}$	Gate threshold voltage	1.0	—	3.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
I_{DSS}	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 60\text{V}, V_{GS} = 0\text{V}$
I_{GSS}	Gate-to-Source forward leakage	—	—	100	μA	$V_{GS} = 20\text{V}$
		—	—	-100		$V_{GS} = -20\text{V}$
Q_g	Total gate charge	—	49	—	nC	$I_D = 30\text{A},$ $V_{DS}=30\text{V},$ $V_{GS} = 10\text{V}$
Q_{gs}	Gate-to-Source charge	—	5.8	—		
Q_{gd}	Gate-to-Drain("Miller") charge	—	14	—		
$t_{d(on)}$	Turn-on delay time	—	7.3	—	ns	$V_{GS}=10\text{V}, V_{DS}=30\text{V},$ $R_{GEN}=1.8\Omega$ $I_D = 30\text{A}$
t_r	Rise time	—	5.1	—		
$t_{d(off)}$	Turn-Off delay time	—	27.8	—		
t_f	Fall time	—	5.2	—		
C_{iss}	Input capacitance	—	1895	—	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 50\text{V}$ $f = 1\text{MHz}$
C_{oss}	Output capacitance	—	102	—		
C_{riss}	Reverse transfer capacitance	—	90	—		

Source-Drain Ratings and Characteristics

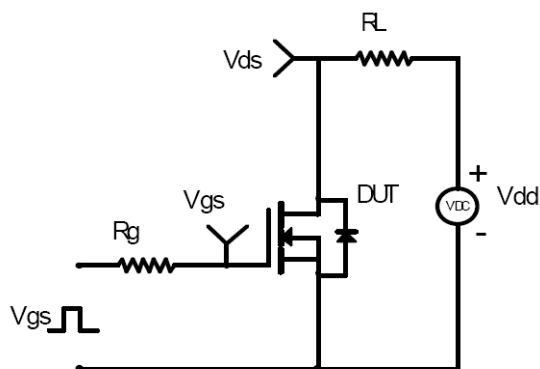
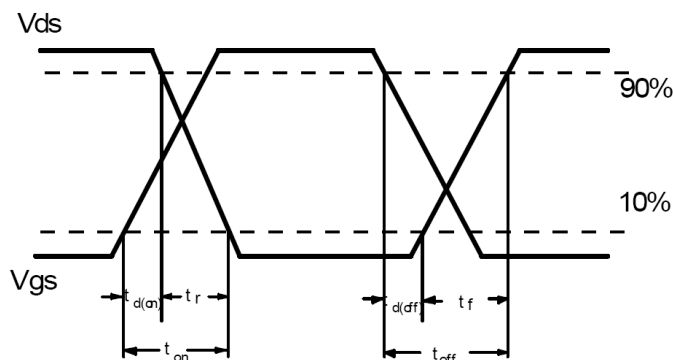
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	33	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode)	—	—	108	A	
V_{SD}	Diode Forward Voltage	—	—	1.2	V	$I_S=30\text{A}, V_{GS}=0\text{V}$
t_{rr}	Reverse Recovery Time	—	26	—	ns	$I_F=30\text{A}, di/dt=100\text{A}/\mu\text{s}$
Q_{rr}	Reverse Recovery Charge	—	37	—	nC	



Test Circuits and Waveforms

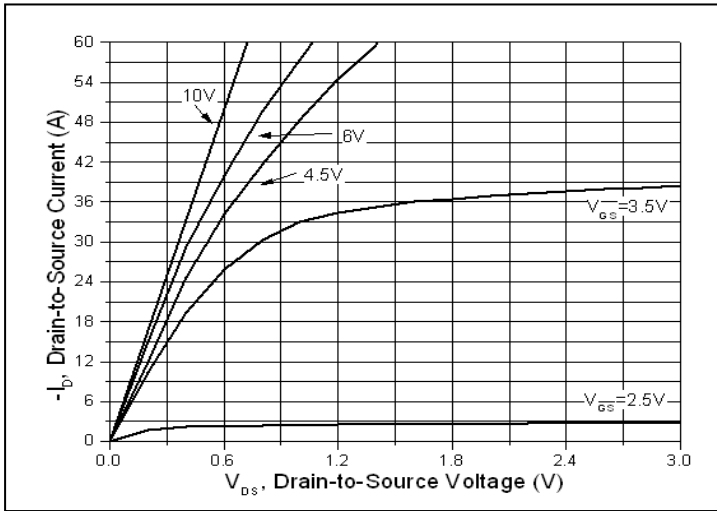
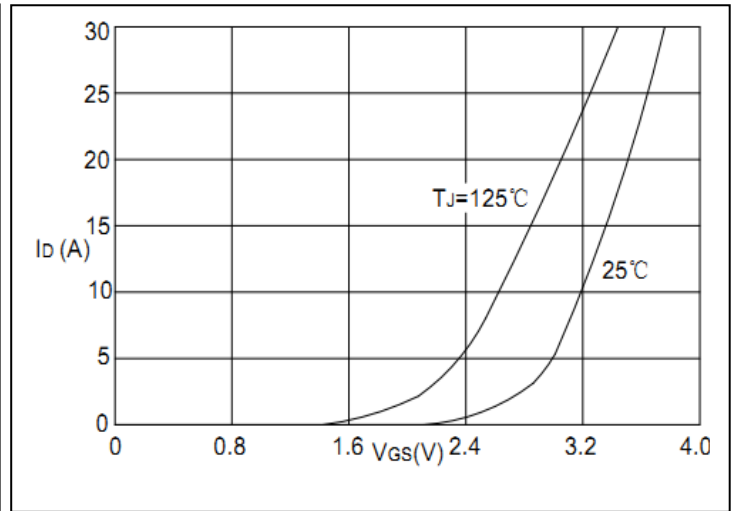
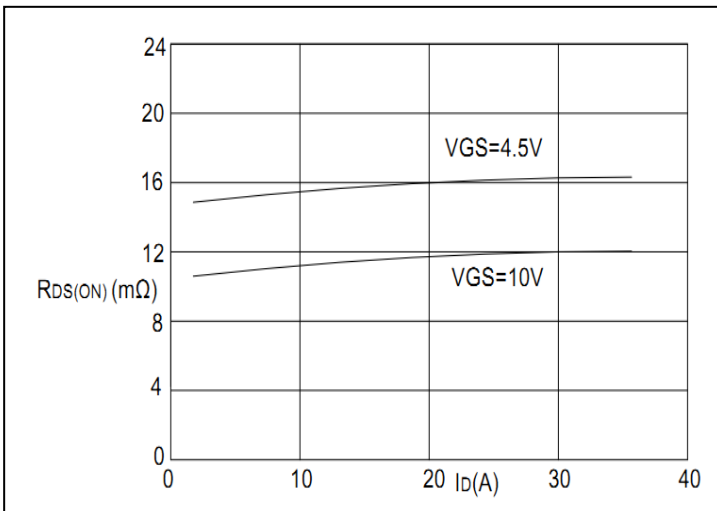
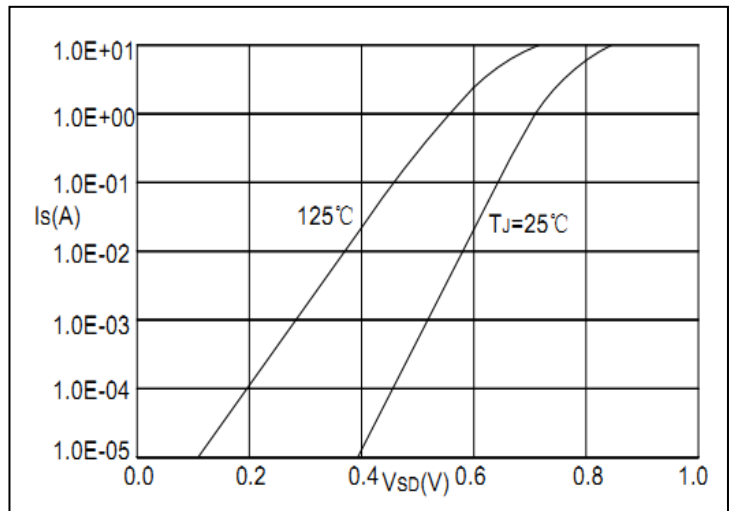
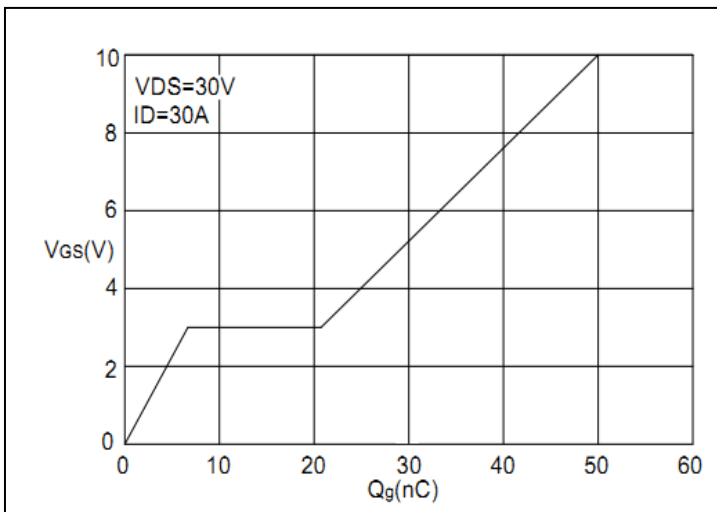
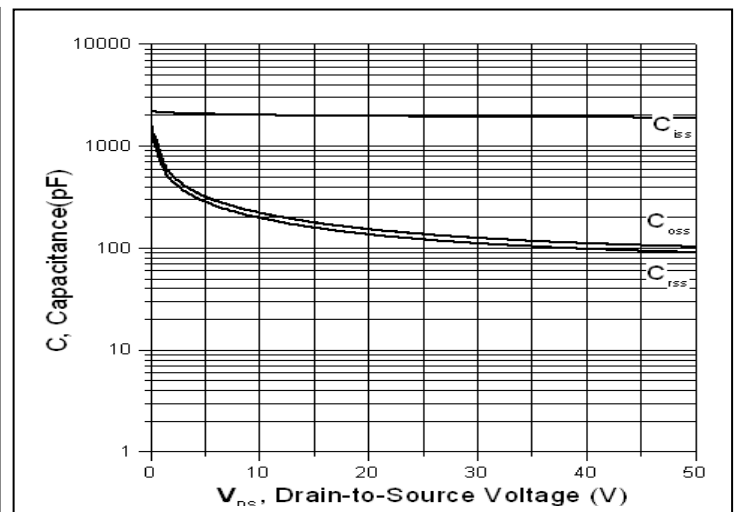
EAS Test Circuit:

Gate Charge Test Circuit:

Switching Time Test Circuit:

Switching Waveforms:


Notes:

- ② Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by Max. Junction temperature.
- ③ The power dissipation PD is based on max. Junction temperature, using junction-to-case thermal resistance.

Typical Electrical and Thermal Characteristics

Figure1. Typical Output Characteristics

Figure2. Transfer Characteristics

Figure 3. Gate Charge Characteristics

Figure 4. Body Diode Characteristics

Figure5. Gate Charge

Figure6. Capacitance

Typical Electrical and Thermal Characteristics

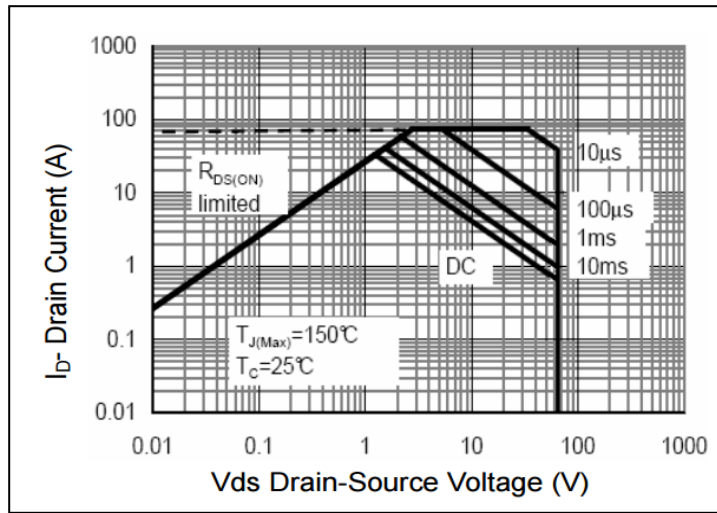


Figure7. Safe Operating Area

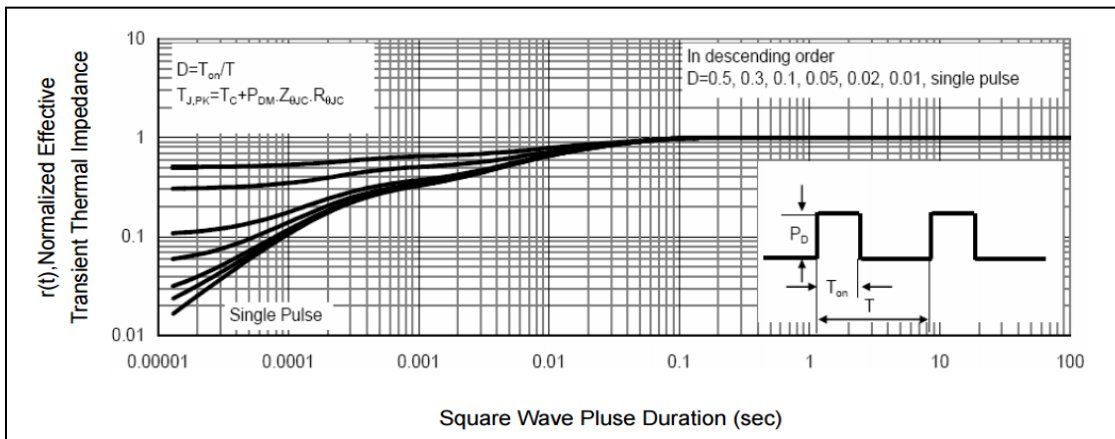
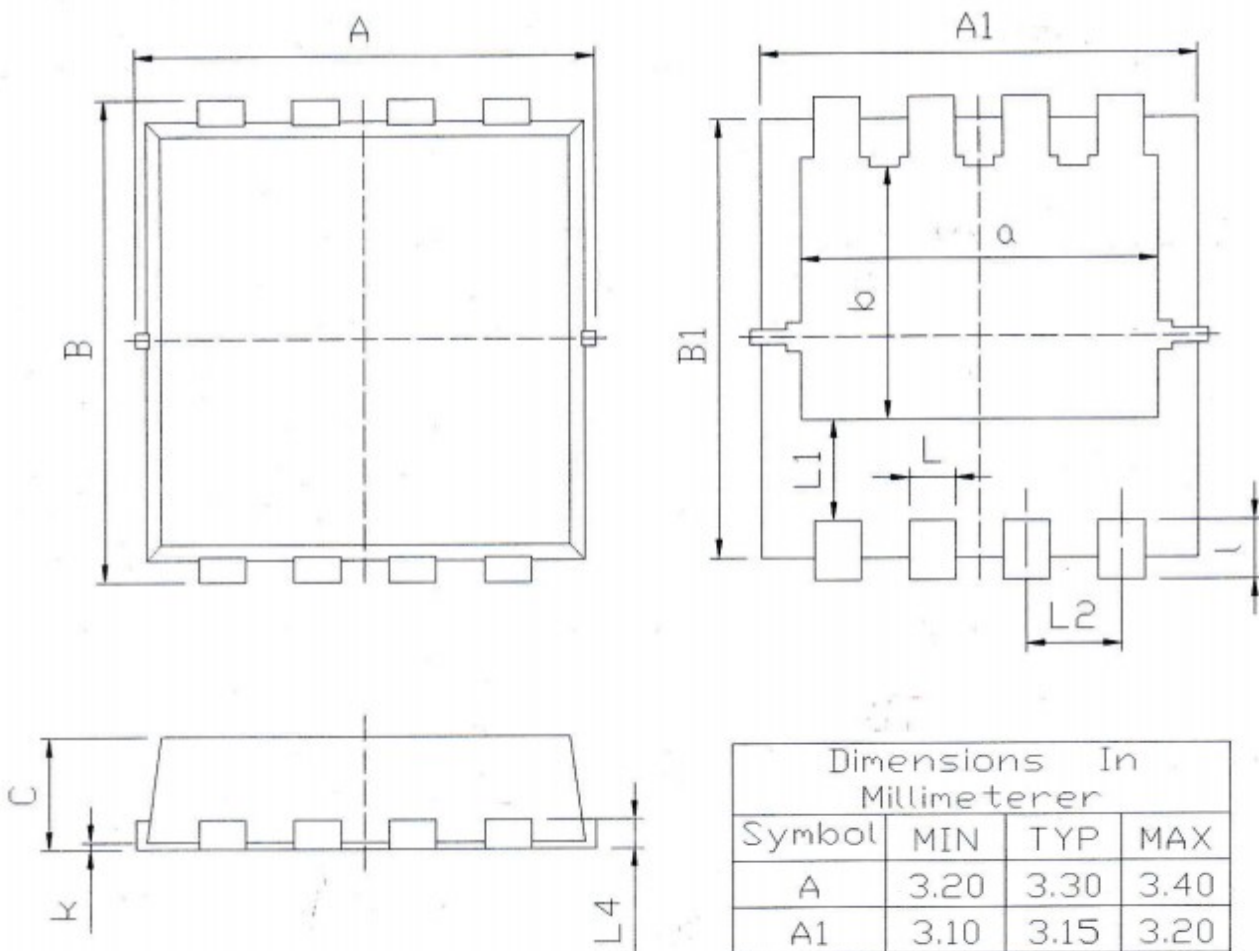


Figure8. Normalized Maximum Transient Thermal Impedance

Mechanical Data:


Dimensions In Millimeterer			
Symbol	MIN	TYP	MAX
A	3.20	3.30	3.40
A1	3.10	3.15	3.20
B	3.20	3.30	3.40
B1	2.95	3.00	3.05
C	0.75	0.80	0.85
L	0.25	0.30	0.35
L1	-	-	0.75
L2	0.55	0.65	0.75
L4	0.14	0.15	0.20
a	2.35	2.45	2.55
b	1.635	1.735	1.835
k	0.00	-	0.05
l	0.30	0.40	0.50

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